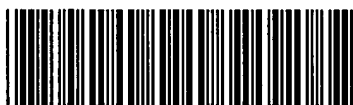


**Search Notes**

Application/Control No.

10/646,793

Examiner

Patricia Leith

Applicant(s)/Patent under  
Reexamination

PAN ET AL.

Art Unit

1655

**SEARCHED**

Class	Subclass	Date	Examiner
424	725	3/31/2006	PL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
424	725	3/31/2006	PL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
updated EAST:JPO,EPO,DERWENT,USPATF ULL,USPGPUBS,OCRBACKFILE	3/31/2006	PL
Inventor name search PALM/EAST	3/31/2006	PL